

Contact Details Registration No. HOKLAS 231 Page 1 of 1

## Smith & Associates Far East Limited – Counterfeit Detection Laboratory

ADDRESS : 1/F, Continental Electric Industrial Building, 17 Wang Chiu Road, Kowloon Bay,

地址 Kowloon, Hong Kong

香港九龍灣宏照道17號康大電業工業大廈1樓

**ENQUIRY** : Ms JIANG Anwen, Operations Manager, Asia

查詢 蔣安文女仕

**TELEPHONE** : 2399 8141

電話

**E-MAIL** : ajiang1@nfsmithfe.com

電郵

CLIENTELE: Public服務對象公眾



Scope of Accreditation

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Issue Date: 24 July 2024 Ref: HOKLAS231-15

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地址 Kowloon, Hong Kong

香港九龍灣宏照道 17 號康大電業工業大厦 1 樓

ACCREDITED TEST : Physical and Mechanical Testing 物理及機械測試

CATEGORY 認可測試類別



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Physical and Mechanical Testing 物理及機械測試		
ITEM TESTED OR MEASURED 測試或量度項目	SPECIFIC TEST OR PROPERTY MEASURED 特定測試或量度的特性	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED 規範、標準方法或應用技術
Integrated Circuit Components		
- Hermetic and nonhermetic solid state surface mount devices	Examination of internal construction of solid state surface mount devices using X-ray inspection system for the following items:  - Broken or missing bond wires  - Die size  - Die construction	IDEA-STD-1010-B: 2011, Section 11.4
- Nonhermetic solid state surface mount devices	Examination of internal construction of solid state surface mount devices using microscope after decapsulation for the following items: Part number - Markings - Manufacturer - Copyright date - Wafer art - No die or blank die - Damaged wafers - OCM rejection dots	IDEA-STD-1010-B: 2011, Section 11.7